

Notice of References Cited	Application/Control No. 10/643,672	Applicant(s)/Patent Under Reexamination RAY ET AL.	
	Examiner Sheela C. Chawan	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Tolga et al., "Indexing large metric spaces for similarity search queries-- IDS. <i>September 1999</i>
*	V	Behzad Dariush et al., "Spatiotemporal analysis of face profiles" Detection, segmentation, and registration-IEEE 1998.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/643,672	Applicant(s)/Patent Under Reexamination RAY ET AL.	
	Examiner Sheela C. Chawan	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,381,346 B1	04-2002	Eraslan, Arsev H.	382/118
	B	US-5,719,951	02-1998	Shackleton et al.	382/118
	C	US-6,128,397	10-2000	Baluja et al.	382/118
	D	US-6,751,340 B2	06-2004	Prokoski, Francine J.	382/118
	E	US-6,272,231 B1	08-2001	Maurer et al.	382/103
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Tolga Bozkaya et al., "indexing large metric spaces for similarity search queries association for computing machinery transactions on database system", pages 1-34, 1999.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<div style="border: 2px solid black; border-radius: 50%; width: 100px; height: 100px; display: flex; align-items: center; justify-content: center; margin: 0 auto;"> <div style="text-align: center;"> <p style="margin: 0;">O I INFORMATION DISCLOSURE CITATION</p> <p style="margin: 0;">(Use several sheets if necessary)</p> <p style="margin: 0;">JAN 20 2004</p> </div> </div>				ATTY DOCKET NO. ITL.0996US (P14028)		SERIAL NO. 10/643,672	
				APPLICANT(S): AJOY K. RAY, ET AL.			
				FILING DATE: August 19, 2003		GROUP ART UNIT: 2621	
				U.S. PATENT DOCUMENTS			
*EXAMINER INITIAL	TRADEMARK	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
scc	A.	6,345,109	02/05/2002	SOUMA ET AL.	382	118	
scc	B.	10/643,467		RAY ET AL.			08/19/2003
	C.						
	D.						
	E.						
	F.						
	G.						
	H.						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	I.						
	J.						
	K.						
	L.						
	M.						
	N.						
	O.						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
scc	P.	A. W.-C. Fu, P. M. S. Chan, Y.-L. Cheung, and Y. S. Moon. "Dynamic vp-tree indexing for n-nearest neighbor search given pair-wise distances". VLDB Journal, 9(2):154-173, June 2000.					
scc	Q.	Bozkaya, Tolga and Meral Ozsoyoglu. "Indexing Large Metric Spaces for Similarity Search Queries. Association for Computing Machinery Transactions on Database System", pages 1-34, 1999.					
scc	R.	C. Xu and J. L. Prince, "Snakes, Shapes, and Gradient Vector Flow," IEEE Trans. Image Proc., pp. 359-369, Mar. 1998.					
	S.						
	T.						
	U.						
	V.						
EXAMINER /Sheela Chawan/				DATE CONSIDERED 12/22/2006			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.